



PSE Technology Corporation

SPECIFICATION FOR APPROVAL

CUSTOMER _____

NOMINAL FREQUENCY _____ 32.768 KHz

PRODUCT TYPE _____ **TYPE G9 SMD CRYSTAL**

SPEC. NO. (P/N) _____ G93270001

CUSTOMER P/N _____

ISSUE DATE _____ Jan.8,2014

VERSION _____ C

| APPROVED | PREPARED | QA |
|--|---------------|-----------------|
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| APPROVED BY CUSTOMER : | | AVL Status |
| Please return one copy with approval to PSE-TW | | |

PSE Technology Corporation

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*Pb-free
*RoHS Compliant
*HF-Halogen Free
*REACH Compliant

*** A company of  **PERICOM Semiconductor Corporation** ***

TYPE G9 SMD CRYSTAL

G93270001

VER. C 3-Oct-11

VERSION HISTORY



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ELECTRICAL SPECIFICATIONS

SRe Part Number : G93270001

| Parameters | Symbol | Specifications | Units | Notes |
|------------------------------|--------|----------------|---------------------|-----------------|
| Nominal Frequency | Fn | 32.768 | KHz | |
| Frequency Tolerance | FT | ± 20 | ppm | at 25 °C ± 5 °C |
| Load Capacitance | CL | 9 | pF | Typ. |
| Drive Level | DL | 0.1 / 0.5 | µW | Typ / Max. |
| Equivalent Series Resistance | ESR | 90 | KΩ | Max. |
| Temperature Coefficient | K | -0.03 | ppm/°C ² | Typ. |
| Operating Temperature Range | TR | -40~85 | °C | |
| Shunt Capacitance | C0 | 7 | pF | Max. |
| Storage Temperature Range | | -55~125 | °C | |
| Aging | | ± 3 | ppm | Max 1st year |
| Insulation Resistance | | 500 | MΩ | Min. |

Reliability (Mechanical and environmental performances)

| No. | Test Items | Conditions | Requirements |
|-----|--------------------|---|---|
| 1 | Bending test | Apply pressure in the direction of the arrow at a rate of about 0.5mm/s until bent width reaches 5mm, and hold for 30 seconds. | <ul style="list-style-type: none">Without mechanical damage such as breaks and satisfy sealing specification.Frequency change: Within ±5ppmEquivalent series resistance(E.S.R) change: Within 5kΩ |
| 2 | Shear test | A static load of 20N(2.04kgf) using a R0.5 scratch tool, shall be applied on the core of the component and in the direction of the arrow and held for 5 seconds. | |
| 3 | Core body strength | A static load of 10N(1.02kgf) using a R0.5 pressure rod shall be applied to the center in the direction of the arrow and held for 10 seconds. | |
| 4 | Vibration | Endurance conditioning by a frequency sweep shall be made. The entire frequency range, from 10Hz to 55Hz and return to 10Hz, shall be transversed in 1 minute. Amplitude (total excursion) : 1.5mm, This motion shall be applied for a period of 2 hours in each of 3 mutually perpendicular axes (a total of 6 hours). For other procedures, refer to JIS C 60068-2-6. | |
| 5 | Shock | Peak acceleration : 9810m/s ² · Duration of the pulse : 1ms, Three successive shock shall be applied 3 times perpendicular axes. For other procedures, refer to JIS C 60068-2-27. | |

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| 6 | Cold | Quartz crystal units shall be stored in the $-40\pm3^{\circ}\text{C}$ atmosphere for 1000 hours. Other procedures conform to JIS C 60068-2-1. | <ul style="list-style-type: none"> Frequency change: Within $\pm 5\text{ppm}$ Equivalent series resistance(E.S.R) change: Within $5\text{k}\Omega$ After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured. | | | | | | | | | | | | | | | |
|--|---|---|--|---|--|---|---------------------------|----------------|---|--------------------|---|---|---------------------------|----------------------------|--|--------------------|----------------|--|
| 7 | Dry heat | Quartz crystal units shall be stored in the $100\pm2^{\circ}\text{C}$ atmosphere for 100 hours. Other procedures conform to JIS C 60068-2-2. | | | | | | | | | | | | | | | | |
| 8 | Damp heat | Quartz crystal units shall be stored in the $40\pm2^{\circ}\text{C}$ atmosphere with 90 to 95% relative humidity for 1000 hours. Other procedures conform to JIS C 60068-2-3. | | | | | | | | | | | | | | | | |
| 9 | Change of temperature | Quartz crystal units shall be subjected successively 100 cycles of temperature change shown below. Other procedures conform to JIS C 0025. <table border="1" data-bbox="452 763 944 943"> <tr> <th></th> <th>Temperature</th> <th>Duration</th> </tr> <tr> <td>1</td> <td>$-40\pm3^{\circ}\text{C}$</td> <td>30min.</td> </tr> <tr> <td>2</td> <td>Normal temperature</td> <td>Within 30 sec.</td> </tr> <tr> <td>3</td> <td>$100\pm2^{\circ}\text{C}$</td> <td>30min.</td> </tr> <tr> <td>4</td> <td>Normal temperature</td> <td>Within 30 sec.</td> </tr> </table> | | Temperature | Duration | 1 | $-40\pm3^{\circ}\text{C}$ | 30min. | 2 | Normal temperature | Within 30 sec. | 3 | $100\pm2^{\circ}\text{C}$ | 30min. | 4 | Normal temperature | Within 30 sec. | |
| | Temperature | Duration | | | | | | | | | | | | | | | | |
| 1 | $-40\pm3^{\circ}\text{C}$ | 30min. | | | | | | | | | | | | | | | | |
| 2 | Normal temperature | Within 30 sec. | | | | | | | | | | | | | | | | |
| 3 | $100\pm2^{\circ}\text{C}$ | 30min. | | | | | | | | | | | | | | | | |
| 4 | Normal temperature | Within 30 sec. | | | | | | | | | | | | | | | | |
| 10 | Sealing | Both the test methods specified below shall be applied. <table border="1" data-bbox="404 1033 992 1212"> <tr> <td>Quartz crystal units shall be soaked in 90°C or higher temperature hot water for 5 minutes.</td> <td> <ul style="list-style-type: none"> Without repetitive leaking bubbles from quartz crystal units. </td> </tr> <tr> <td>Quartz crystal units shall be tested by Mass spectrometric leakage detector to measure the leakage rate of helium gas.</td> <td> <ul style="list-style-type: none"> $1\times 10^{-9} \text{ Pa}\cdot\text{m}^3/\text{s}$ or less </td> </tr> </table> | Quartz crystal units shall be soaked in 90°C or higher temperature hot water for 5 minutes. | <ul style="list-style-type: none"> Without repetitive leaking bubbles from quartz crystal units. | Quartz crystal units shall be tested by Mass spectrometric leakage detector to measure the leakage rate of helium gas. | <ul style="list-style-type: none"> $1\times 10^{-9} \text{ Pa}\cdot\text{m}^3/\text{s}$ or less | | | | | | | | | | | | |
| Quartz crystal units shall be soaked in 90°C or higher temperature hot water for 5 minutes. | <ul style="list-style-type: none"> Without repetitive leaking bubbles from quartz crystal units. | | | | | | | | | | | | | | | | | |
| Quartz crystal units shall be tested by Mass spectrometric leakage detector to measure the leakage rate of helium gas. | <ul style="list-style-type: none"> $1\times 10^{-9} \text{ Pa}\cdot\text{m}^3/\text{s}$ or less | | | | | | | | | | | | | | | | | |
| 11 | Aging | Quartz crystal units shall be stored in the $85\pm3^{\circ}\text{C}$ atmosphere for 720 ± 12 hours. | <ul style="list-style-type: none"> Frequency change: Within $\pm 5\text{ppm}$ Equivalent series resistance(E.S.R) change: Within $5\text{k}\Omega$ After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured. | | | | | | | | | | | | | | | |
| 12 | Solder-ability | Terminals coated with flux shall be immersed in the solder bath for 3.5 ± 0.5 seconds. <table border="1" data-bbox="452 1527 944 1796"> <tr> <th></th> <th>Items</th> <th>Conditions</th> </tr> <tr> <td>1</td> <td>Solder</td> <td>Sn-3.0Ag-0.5Cu</td> </tr> <tr> <td>2</td> <td>Flux</td> <td>Approximately 25wt% methanol(JIS K 8891) solution of resin(JIS K 5902).</td> </tr> <tr> <td>3</td> <td>Solder temperature</td> <td>$255\pm 5^{\circ}\text{C}$</td> </tr> </table> | | Items | Conditions | 1 | Solder | Sn-3.0Ag-0.5Cu | 2 | Flux | Approximately 25wt% methanol(JIS K 8891) solution of resin(JIS K 5902). | 3 | Solder temperature | $255\pm 5^{\circ}\text{C}$ | <ul style="list-style-type: none"> Minimum 95% of immersed terminal shall be covered with new uniform solder. | | | |
| | Items | Conditions | | | | | | | | | | | | | | | | |
| 1 | Solder | Sn-3.0Ag-0.5Cu | | | | | | | | | | | | | | | | |
| 2 | Flux | Approximately 25wt% methanol(JIS K 8891) solution of resin(JIS K 5902). | | | | | | | | | | | | | | | | |
| 3 | Solder temperature | $255\pm 5^{\circ}\text{C}$ | | | | | | | | | | | | | | | | |

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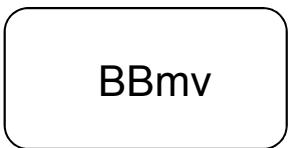
| | | | |
|----|------------------------------|--|---|
| 13 | Resistance to soldering heat | <p>Reflow soldering method</p> <p>Temperature profile</p> <p>Peak temperature: 260±5°C for within 5seconds. Soldering temperature: 220°C or higher for 60±10 seconds. Pre-heating temperature: 160±10°C for 90±10 seconds. Quartz crystal units which is put on PCB shall be through reflow soldering furnace twice with the condition shown above.</p> | <ul style="list-style-type: none"> Frequency change: Within ±5ppm Equivalent series resistance (E.S.R) change: Within 10kΩ After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured. Without distinct deformation in appearance. |
| 14 | Solubility to resistance | <p>Soldering iron method</p> <p>Terminals shall be applied 400±10°C soldering iron heat for 3.5±0.5 seconds twice.</p> <p>Soak cleaning</p> <p>Quartz crystal units shall be soaked in isopropyl alcohol at normal temperature for 90 seconds.</p> | <ul style="list-style-type: none"> Frequency change: Within ±5ppm Equivalent series resistance(E.S.R) change: Within 5kΩ After conditioning, quartz crystal units shall be subjected to standard atmospheric conditions for 1 hour, and measured. Without distinct deformation in appearance. <ul style="list-style-type: none"> Without mechanical damage such as breaks and satisfy sealing specification. Frequency change: Within ±5ppm Equivalent series resistance(E.S.R) change: Within 5kΩ Without distinct deformation in appearance. Marking shall be legible. |

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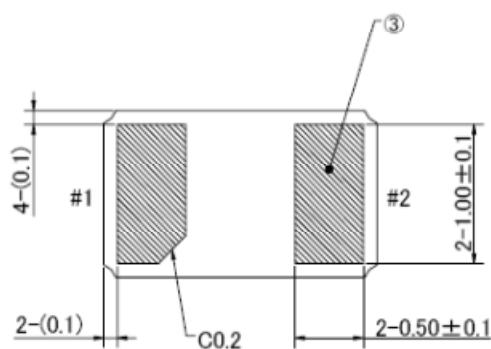
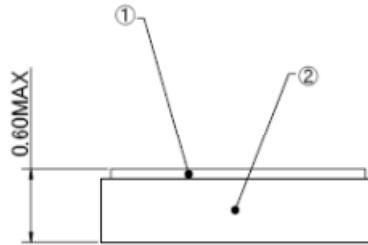
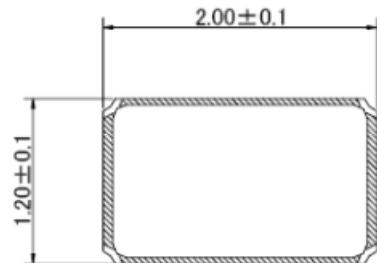
Marking



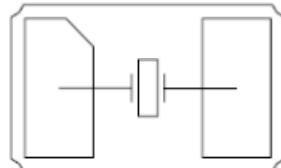
m
Date Code

v
Factory Code

Dimensions (Units: mm)

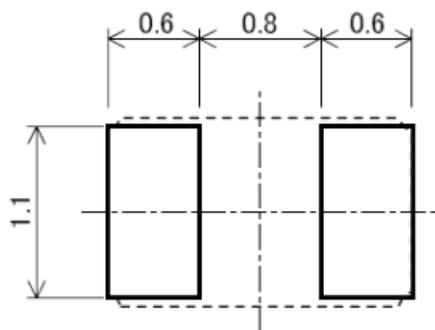


内部接続図
Internal connection



〈Top View〉

Land dimensions(unit: mm)

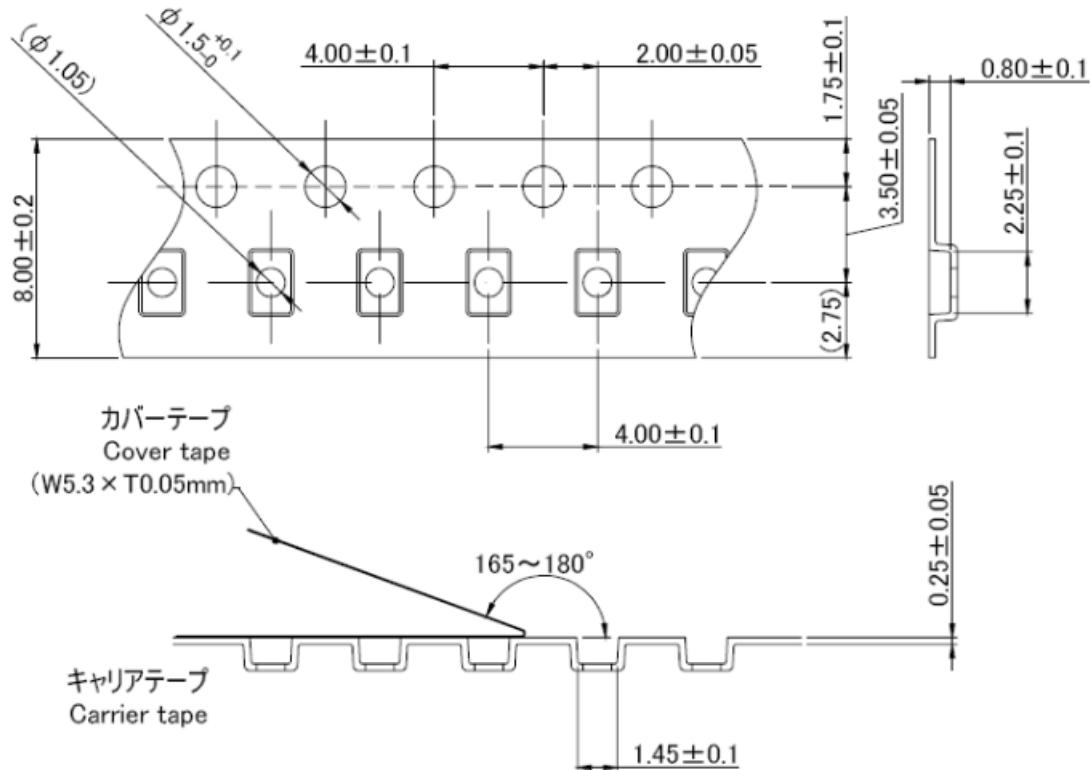


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TAPING



REEL

Reel

